MOSFET – Power, P-Channel, SOIC-8 -30 V, -11.4 A

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- SOIC-8 Surface Mount Package Saves Board Space
- This is a Pb-Free Device

Applications

- Load Switches
- Notebook PC's
- Desktop PC's

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Ratir	Symbol	Value	Unit		
Drain-to-Source Voltage			V_{DSS}	-30	V
Gate-to-Source Voltage			V _{GS}	±20	V
Continuous Drain		T _A = 25°C	I _D	-8.9	Α
Current R _{θJA} (Note 1)		T _A = 70°C		-7.1	
Power Dissipation $R_{\theta JA}$ (Note 1)		T _A = 25°C	P _D	1.52	W
Continuous Drain]	T _A = 25°C	I _D	-6.6	Α
Current R _{θJA} (Note 2)	Steady	T _A = 70°C		-5.3	
Power Dissipation $R_{\theta JA}$ (Note 2)	State	T _A = 25°C	P _D	0.84	W
Continuous Drain		T _A = 25°C	I _D	-11.4	Α
Current R _{θJA} t < 10 s (Note 1)		T _A = 70°C		-9.3	
Power Dissipation $R_{\theta JA} t < 10 s \text{ (Note 1)}$		T _A = 25°C	P _D	2.5	W
Pulsed Drain Current	$T_A = 25^{\circ}C,$ $t_p = 10 \ \mu s$		I _{DM}	-46	Α
Operating Junction and Storage Temperature			T _J , T _{STG}	-55 to +150	°C
Source Current (Body Diode)			I _S	-2.1	Α
Single Pulse Drain-to-Source Avalanche Energy T_J = 25°C, V_{DD} = 30 V, V_{GS} = 10 V, I_L = 20 A_{pk} , L = 1.0 mH, R_G = 25 Ω			EAS	200	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- Surface-mounted on FR4 board using 1 inch sq pad size, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.

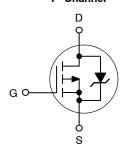


ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(on)} Max	I _D Max
-30 V	12 mΩ @ –10 V	-11.4 A
	19 mΩ @ -4.5 V	11.470

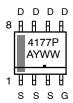
P-Channel



MARKING DIAGRAM **& PIN ASSIGNMENT**



SOIC-8 **CASE 751** STYLE 12



4177P = Device Code = Assembly Location = Year WW = Work Week

= Pb-Free Package

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMS4177PR2G	SOIC-8 (Pb-Free)	2500/Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

THERMAL RESISTANCE RATINGS

Rating	Symbol	Max	Unit
Junction-to-Ambient - Steady State (Note 3)	$R_{ hetaJA}$	82	
Junction-to-Ambient - t≤10 s (Note 3)	$R_{ hetaJA}$	50	°C/W
Junction-to-FOOT (Drain)	$R_{\theta JF}$	20	-0/00
Junction-to-Ambient - Steady State (Note 4)	$R_{ hetaJA}$	148	

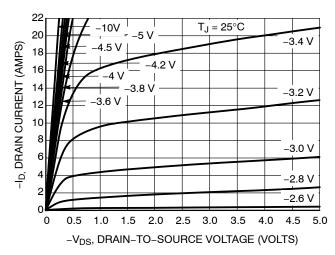
- Surface-mounted on FR4 board using 1 inch sq pad size, 1 oz Cu.
 Surface-mounted on FR4 board using the minimum recommended pad size.

ELECTRICAL CHARACTERISTICS (T = 25°C unless otherwise noted)ik

Characteristic	Symbol	Test Con	dition	Min	Тур	Max	Unit
OFF CHARACTERISTICS	•						•
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$		-30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	$V_{(BR)DSS}/T_J$				29		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V, V _{DS} = -24 V	$T_{J} = 25^{\circ}C$ $T_{J} = 85^{\circ}C$			-1.0 -5.0	μΑ
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V ₀				±100	nA
ON CHARACTERISTICS (Note 5)	400	20 7		l	<u>I</u>		1
Gate Threshold Voltage	V _{GS(TH)}	V _{GS} = V _{DS} , I _D	_ = -250 นA	-1.5		-2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J	GG 1567 15			6.0		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	$V_{GS} = -10 \text{ V}$	$I_D = -11.4 \text{ A}$		10	12	~ 0
		$V_{GS} = -4.5 \text{ V}$	I _D = -9.1 A		15	19	mΩ
Forward Transconductance	9FS	V _{DS} = −1.5 V	I _D = -11.4 A		30		S
CHARGES, CAPACITANCES AND GATE F	RESISTANCE						
Input Capacitance	C _{ISS}				3100		
Output Capacitance	C _{OSS}	$V_{GS} = 0 \text{ V, f} = 1.0 \text{ MHz,}$ $V_{DS} = -24 \text{ V}$)	550		pF
Reverse Transfer Capacitance	C _{RSS}	- 53			370		1
Total Gate Charge	Q _{G(TOT)}				29		1
Threshold Gate Charge	Q _{G(TH)}	$V_{GS} = -4.5 \text{ V}, V_{DS} = -15 \text{ V},$			3.3		7 ,,,
Gate-to-Source Charge	Q _{GS}	I _D = -1	1.4 A		10		nC
Gate-to-Drain Charge	Q_{GD}				13		
Total Gate Charge	Q _{G(TOT)}	$V_{GS} = -10 \text{ V}, V_{DS} = -15 \text{ V},$ $I_D = -11.4 \text{ A},$			55		nC
Gate Resistance	R_{G}				2.0	4.0	Ω
SWITCHING CHARACTERISTICS (Note 6)							
Turn-On Delay Time	t _{d(ON)}				18		ns
Rise Time	t _r	$V_{GS} = -10 \text{ V, V}$ $I_{D} = -1.0 \text{ A, F}$	_{DD} = -15 V,		13		
Turn-Off Delay Time	t _{d(OFF)}	$I_D = -1.0 \text{ A}, F$	$R_{G} = 6.0 \Omega$		64		
Fall Time	t _f				36		1
DRAIN-TO-SOURCE CHARACTERISTICS	3						
Forward Diode Voltage	V_{SD}	V _{GS} = 0 V	T _J = 25°C		-0.73	-1.0	V
		$I_D = -2.1 \text{ A}$	T _J = 125°C		0.54		
Reverse Recovery Time	t _{RR}	$V_{GS} = 0 \text{ V, } d_{IS}/d_t = 100 \text{ A/}\mu\text{s,}$ $I_S = -2.1 \text{ A}$			34		1
Charge Time	Ta				18		- ns
Discharge Time	T _b				16		
Reverse Recovery Time	Q_{RR}				30		nC

- 5. Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
- 6. Switching characteristics are independent of operating junction temperatures.

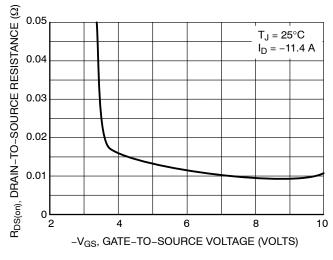
TYPICAL PERFORMANCE CURVES



 $V_{DS} \ge 10 \text{ V}$ 20 -ID, DRAIN CURRENT (AMPS) 18 16 14 12 10 T_J = 125°C $T_J = 25^{\circ}C$ 2 $T_{,l} = -55^{\circ}C$ 0**└** 1.5 2.0 3.0 3.5 4.0 -V_{GS}, GATE-TO-SOURCE VOLTAGE (VOLTS)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



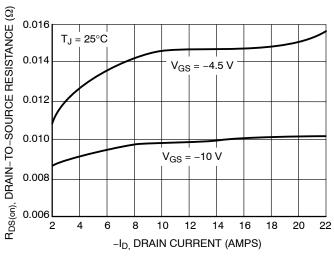
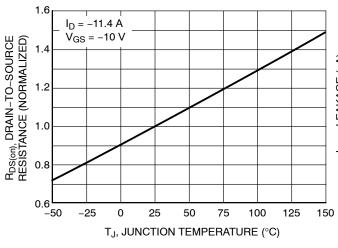


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



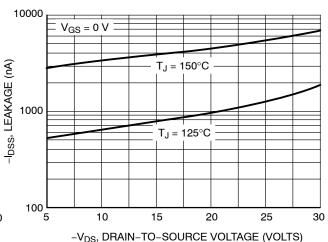


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL PERFORMANCE CURVES

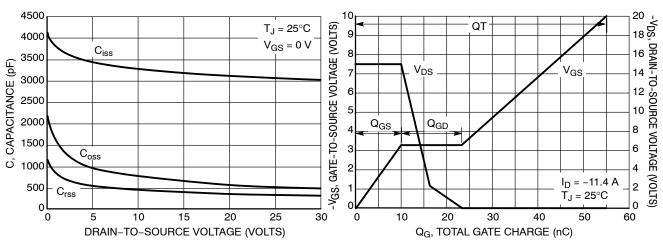


Figure 7. Capacitance Variation

Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge

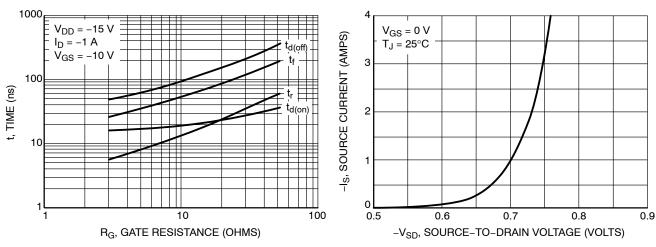


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

Figure 10. Diode Forward Voltage vs. Current

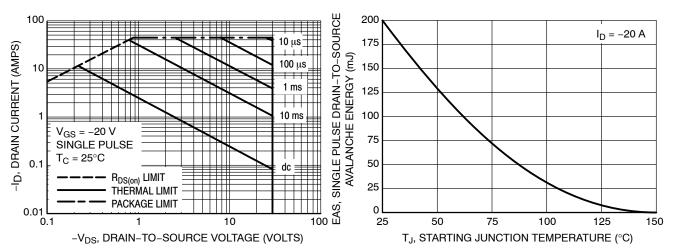


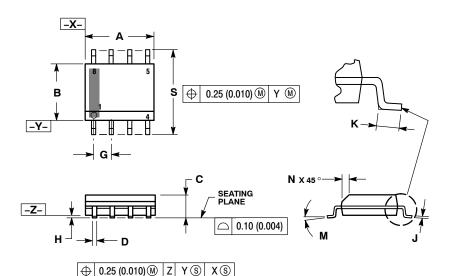
Figure 11. Maximum Rated Forward Biased Safe Operating Area

Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature



SOIC-8 NB CASE 751-07 **ISSUE AK**

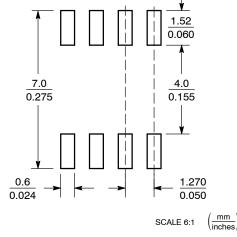
DATE 16 FEB 2011



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIMETERS		INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	4.80	5.00	0.189	0.197	
В	3.80	4.00	0.150	0.157	
C	1.35	1.75	0.053	0.069	
D	0.33	0.51	0.013	0.020	
G	1.27 BSC		0.050 BSC		
Н	0.10	0.25	0.004	0.010	
7	0.19	0.25	0.007	0.010	
K	0.40	1.27	0.016	0.050	
M	0 °	8 °	0 °	8 °	
N	0.25	0.50	0.010	0.020	
S	5.80	6.20	0.228	0.244	

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

GENERIC MARKING DIAGRAM*



XXXXX = Specific Device Code = Assembly Location = Wafer Lot

= Year = Work Week = Pb-Free Package

AYWW Ŧ \mathbb{H} Discrete **Discrete** (Pb-Free) XXXXXX = Specific Device Code

AYWW

XXXXXX

= Assembly Location Α = Year ww = Work Week = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb–Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

STYLES ON PAGE 2

DOCUMENT NUMBER:	98ASB42564B	Electronic versions are uncontrolled except when accessed directly from the Document Rep Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	SOIC-8 NB		PAGE 1 OF 2	

ON Semiconductor and un are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

SOIC-8 NB CASE 751-07 ISSUE AK

DATE 16 FEB 2011

STYLE 1: PIN 1. EMITTER 2. COLLECTOR 3. COLLECTOR 4. EMITTER 5. EMITTER 6. BASE 7. BASE 8. EMITTER	STYLE 2: PIN 1. COLLECTOR, DIE, #1 2. COLLECTOR, #1 3. COLLECTOR, #2 4. COLLECTOR, #2 5. BASE, #2 6. EMITTER, #2 7. BASE, #1 8. EMITTER, #1	STYLE 3: PIN 1. DRAIN, DIE #1 2. DRAIN, #1 3. DRAIN, #2 4. DRAIN, #2 5. GATE, #2 6. SOURCE, #2 7. GATE, #1 8. SOURCE, #1	
STYLE 5: PIN 1. DRAIN 2. DRAIN 3. DRAIN 4. DRAIN 5. GATE 6. GATE 7. SOURCE 8. SOURCE	STYLE 6: PIN 1. SOURCE 2. DRAIN 3. DRAIN 4. SOURCE 5. SOURCE 6. GATE 7. GATE 8. SOURCE	STYLE 7: PIN 1. INPUT 2. EXTERNAL BYPASS 3. THIRD STAGE SOURCE 4. GROUND 5. DRAIN 6. GATE 3 7. SECOND STAGE Vd 8. FIRST STAGE Vd	STYLE 8: PIN 1. COLLECTOR, DIE #1 2. BASE, #1 3. BASE, #2 4. COLLECTOR, #2 5. COLLECTOR, #2 6. EMITTER, #2 7. EMITTER, #1 8. COLLECTOR, #1
STYLE 9: PIN 1. EMITTER, COMMON 2. COLLECTOR, DIE #1 3. COLLECTOR, DIE #2 4. EMITTER, COMMON 5. EMITTER, COMMON 6. BASE, DIE #2 7. BASE, DIE #1 8. EMITTER, COMMON	STYLE 10: PIN 1. GROUND 2. BIAS 1 3. OUTPUT 4. GROUND 5. GROUND 6. BIAS 2 7. INPUT 8. GROUND STYLE 14: PIN 1. N-SOURCE 2. N-GATE 3. P-SOURCE	STYLE 11: PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2 4. GATE 2 5. DRAIN 2 6. DRAIN 2 7. DRAIN 1 8. DRAIN 1	STYLE 12: PIN 1. SOURCE 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
STYLE 13: PIN 1. N.C. 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN	STYLE 14: PIN 1. N-SOURCE 2. N-GATE 3. P-SOURCE 4. P-GATE 5. P-DRAIN 6. P-DRAIN 7. N-DRAIN 8. N-DRAIN	8. DHAIN 1 STYLE 15: PIN 1. ANODE 1 2. ANODE 1 3. ANODE 1 4. ANODE 1 5. CATHODE, COMMON 6. CATHODE, COMMON 7. CATHODE, COMMON 8. CATHODE, COMMON	STYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2 4. BASE, DIE #2 5. COLLECTOR, DIE #2 6. COLLECTOR, DIE #2 7. COLLECTOR, DIE #1 8. COLLECTOR, DIE #1
STYLE 17: PIN 1. VCC 2. V2OUT 3. V1OUT 4. TXE 5. RXE 6. VEE 7. GND 8. ACC	STYLE 18: PIN 1. ANODE 2. ANODE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. CATHODE 8. CATHODE	STYLE 19: PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2 4. GATE 2 5. DRAIN 2 6. MIRROR 2 7. DRAIN 1 8. MIRROR 1	STYLE 20: PIN 1. SOURCE (N) 2. GATE (N) 3. SOURCE (P) 4. GATE (P) 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
6. VEE 7. GND 8. ACC STYLE 21: PIN 1. CATHODE 1 2. CATHODE 2 3. CATHODE 3 4. CATHODE 4 5. CATHODE 5 6. COMMON ANODE 7. COMMON ANODE 8. CATHODE 6	STYLE 22: PIN 1. I/O LINE 1 2. COMMON CATHODE/VCC 3. COMMON CATHODE/VCC 4. I/O LINE 3 5. COMMON ANODE/GND 6. I/O LINE 4 7. I/O LINE 5 8. COMMON ANODE/GND	STYLE 23: PIN 1. LINE 1 IN 2. COMMON ANODE/GND 3. COMMON ANODE/GND 4. LINE 2 IN 5. LINE 2 OUT 6. COMMON ANODE/GND 7. COMMON ANODE/GND 8. LINE 1 OUT	0 COLLECTOR/ANODE
STYLE 25: PIN 1. VIN 2. N/C 3. REXT 4. GND 5. IOUT 6. IOUT 7. IOUT 8. IOUT	STYLE 26: PIN 1. GND 2. dv/dt 3. ENABLE 4. ILIMIT 5. SOURCE 6. SOURCE 7. SOURCE 8. VCC	STYLE 27: PIN 1. ILIMIT 2. OVLO 3. UVLO 4. INPUT+ 5. SOURCE 6. SOURCE 7. SOURCE 8. DRAIN	STYLE 28: PIN 1. SW_TO_GND 2. DASIC_OFF 3. DASIC_SW_DET 4. GND 5. V_MON 6. VBULK 7. VBULK 8. VIN
STYLE 29: PIN 1. BASE, DIE #1 2. EMITTER, #1 3. BASE, #2 4. EMITTER, #2 5. COLLECTOR, #2 6. COLLECTOR, #2 7. COLLECTOR, #1 8. COLLECTOR, #1	STYLE 30: PIN 1. DRAIN 1 2. DRAIN 1 3. GATE 2 4. SOURCE 2 5. SOURCE 1/DRAIN 2 6. SOURCE 1/DRAIN 2 7. SOURCE 1/DRAIN 2 8. GATE 1		

DOCUMENT NUMBER	98ASB42564B Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION	: SOIC-8 NB		PAGE 2 OF 2

ON Semiconductor and IN are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

onsemi, ONSEMI, and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. onsemi reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does **onsemi** assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using **onsemi** products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by **onsemi**. "Typical" parameters which may be provided in **onsemi** data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. **onsemi** does not convey any license under any of its intellectual property rights nor the rights of others. **onsemi** products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use **onsemi** products for any such unintended or unauthorized application, Buyer shall indemnify and hold **onsemi** and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that **onsemi** was negligent regarding the design or manufacture of the part. **onsemi** is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT: Email Requests to: orderlit@onsemi.com

onsemi Website: www.onsemi.com

TECHNICAL SUPPORT North American Technical Support: Voice Mail: 1 800–282–9855 Toll Free USA/Canada

Phone: 011 421 33 790 2910

Europe, Middle East and Africa Technical Support:

Phone: 00421 33 790 2910

For additional information, please contact your local Sales Representative